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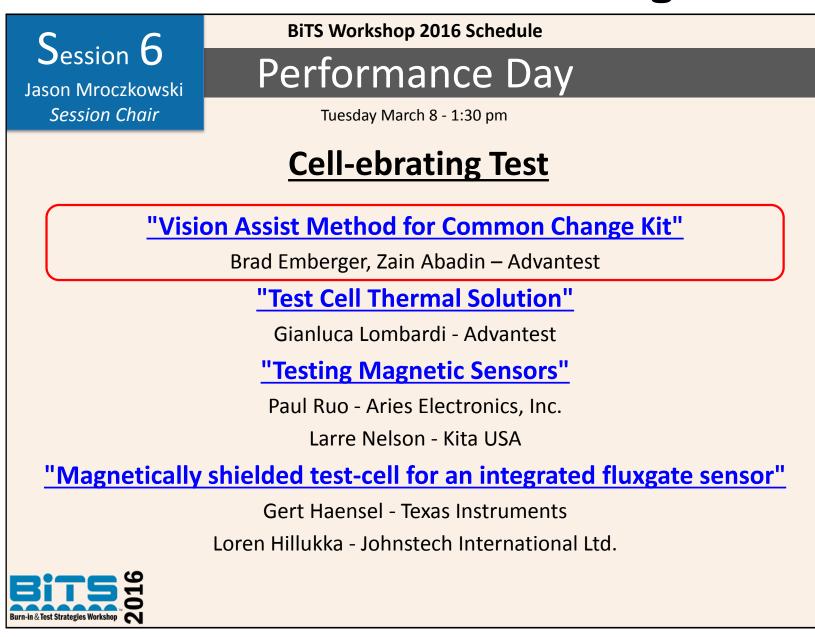
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# Vision Assist Method for Common Change Kit

Zain Abadin Brad Emberger Advantest



**Bits 2016** 

2016 BiTS Workshop March 6 - 9, 2016

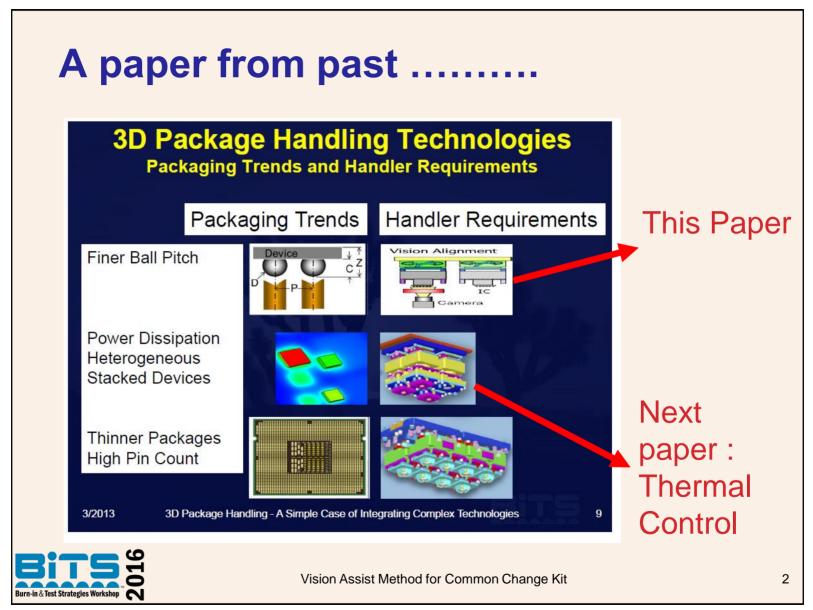


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Session 6 Presentation 1

Cell-ebrating Test- Test Cell - 1 of 2



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#### Cell-ebrating Test- Test Cell - 1 of 2

## Contents

- Mechanical vs Vision Alignment
- Why Vision Alignment?
- Target Applications
- Common Change Kit
- Examples of Cost Savings
- Conclusions



Vision Assist Method for Common Change Kit

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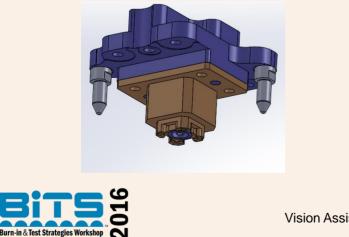
# **Mechanical vs Vision Alignment**

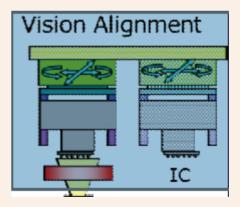
#### **Mechanical Alignment**

- Uses guide pins and precision features to align parts together
- Mechanical features wear out and require replacement
- Tolerance is limited by machining capabilities, device tolerances and life of hardware

#### **Vision Alignment**

- Uses a Camera to determine device location
- Chucks can individually adjust aligning the device to socket
- Tolerance limited by camera resolution



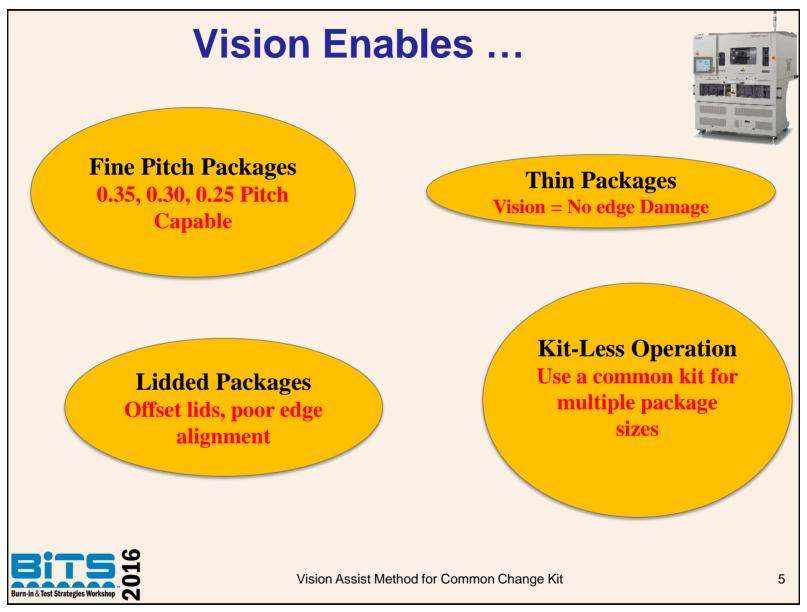


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254 devices Site1

Site2

Site3

Site4

Site5

Site6

Site7

Site8

Site9 Site10

Site11

Site12

# **Fine Pitch Packages**

- Production Proven Technology
- Demonstrated > 99% yield on X12
  - Device pitch = 0.35 pitch

100%

100%

100%

100%

100%

100%

100%

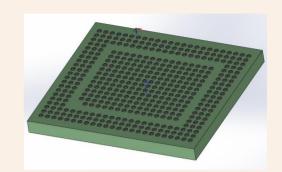
100% 100%

100%

100%

100%

– Vision "on the fly" alignment







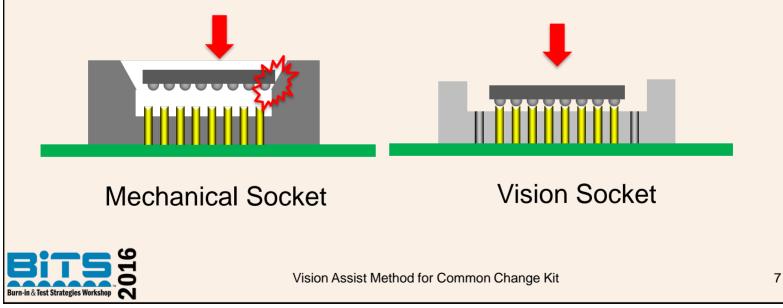
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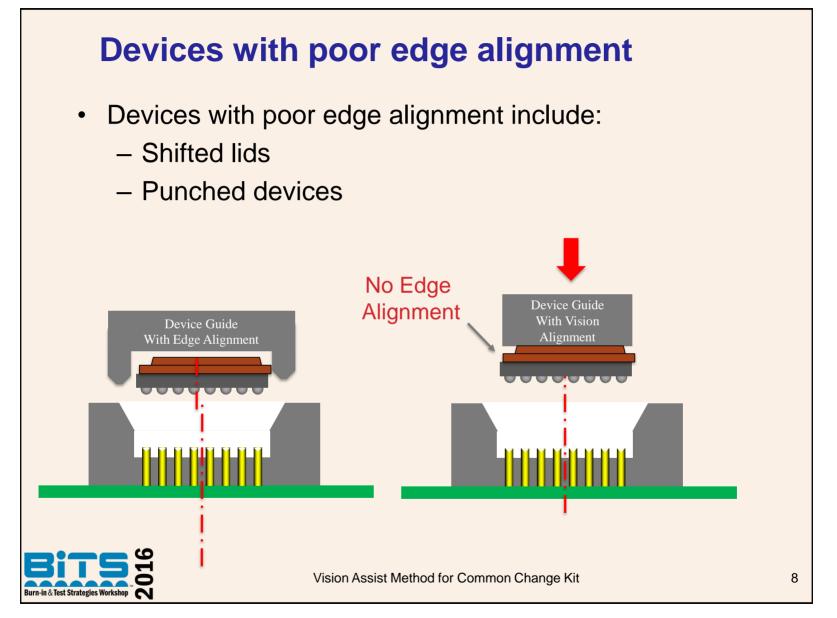
#### Thin Packages – No Edge Contact

- Traditional Mechanical Alignment Socket physically guides device to final position
  - Mechanical alignment method = Edge contact, concern of substrate damage
  - Vision alignment = No edge contact



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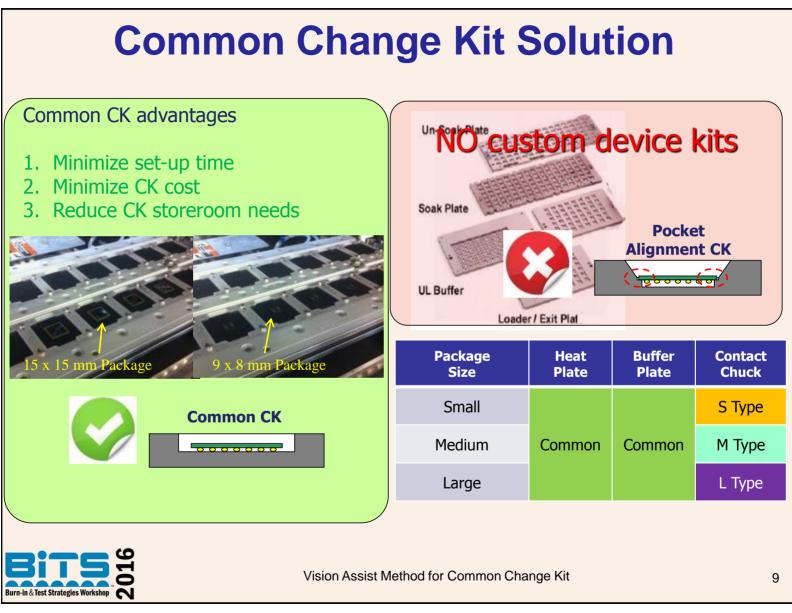


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#### **Cost Savings with Common Change Kits**

- Major Cost Savings Include:
  - Eliminate new change kit costs
  - Greatly reduce change over time
  - Reduced inventory space & hardware management
  - Simplify component design
    - Lower cost
    - Shorter lead times



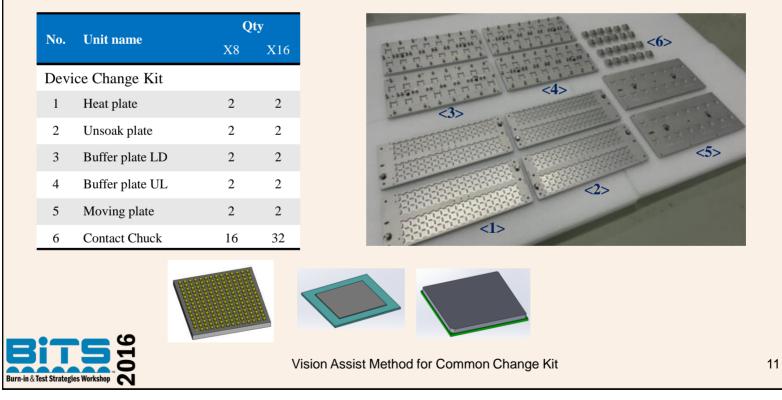
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#### **Mechanical Change Kits**

- Traditional Change kits require one kit for each package size
- This requires a large number of different kits



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# **Kit Hardware Annual Cost Savings**

Example 1:	
10 Systems: ~	179K Savings

Example 2:	
100 Systems: ~	1.8M Savings

Change Kit Costs								
	Assumes 4 kits per system							
		10 Sy	stems	100 5	100 Systems			
Test Site	~ Kit Cost	4 kits/	system	4 kits	4 kits/system			
	Cost	Kits Cost		Kits	Cost			
X2	\$3,000	15	\$45,000	150	\$450,000			
X4	\$6,000	12	\$72,000	120	\$720,000			
X8	\$10,000	8	\$80,000	80	\$800,000			
X16	\$18,000	5	\$90,000	50	\$900,000			
Total		40	\$287,000	400	\$2,870,000			

Change Kit Costs - Vision								
	Assumes 1.5 kits per system							
		10 Sy	stems	100 S	100 Systems			
Test Site	~ Kit Cost	1.5 kits,	/system	1.5 kits	kits/system			
	Cost	Kits	Cost	Kits	Cost			
X2	\$3,000	6	\$18,000	65	\$195,000			
X4	\$6,000	4	\$24,000	45	\$270,000			
X8	\$10,000	3	\$30,000	25	\$250,000			
X16	\$18,000	2	\$36,000	15	\$270,000			
Total		15	\$108,000	150	\$985,000			



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# **Reduced Labor Costs**

#### Reduced

- Labor Costs
- Down Time

Change Over Costs - Mechanical								
Assumes 2 hrs/ Change & \$30/hr labor								
	10 sys	10 sys 100 Sys 10 sys 100 Sys 10 sys 100 Sys 100 Sys 100 Sys						
Kit changes / week	1		3		5		7	
Weekly	\$600	6K	1.8K	18K	ЗК	30K	4.2K	42K
Annual Costs	31K	312K	93K	936K	156K	1,560K	218K	2,184K

Change Over Costs - Vision								
Assumes 0.5 hrs/ Change & \$30/hr labor								
	10 sys	100 Sys	10 sys	100 Sys	10 sys	100 Sys	10 sys	100 Sys
Kit changes / week	1		3		5		7	
Weekly	\$150	\$1,500	\$450	\$4,500	\$750	\$7,500	\$1,050	\$10,500
Annual Costs	\$7,800	\$78,000	\$23,400	\$234,000	\$39,000	\$390,000	\$54,600	\$546,000

#### Improved OEE Shorter Time to Market

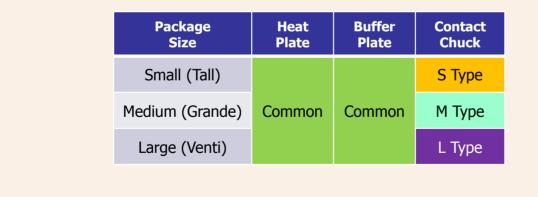


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# Improved Kit Management

- Storage Reduced storage space, common hardware stays on the handler
- Procurement Fewer skews to purchase and manage





Vision Assist Method for Common Change Kit

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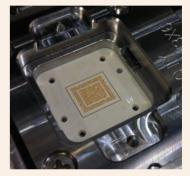
## Simplified Design... Sockets

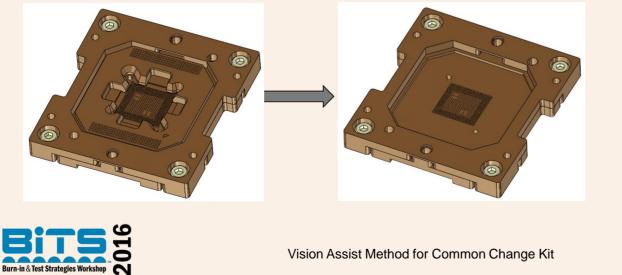
Fine tolerance socket features are eliminated reducing socket cost

• Reduced design time

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- Reduced manufacturing time
- Reduced maintenance No alignment features to wear out





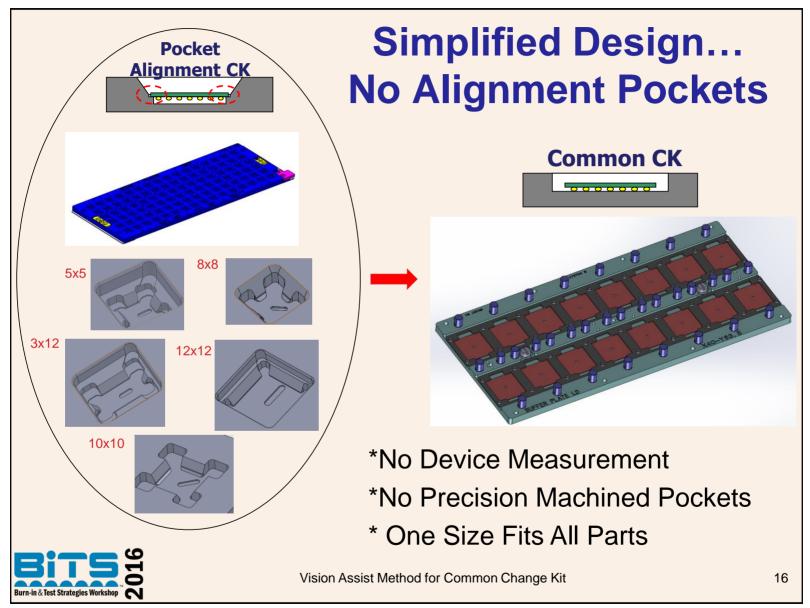
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# **Conclusions**

- Vision delivers significant cost reductions by using common hardware across multiple package sizes and types.
- Beyond cost of the initial hardware, and OEE improvements, significant savings can be realized in reducing management cost including: procurement, storage, instillation/de-instillation of kit on the system
- Vision is an enabling technology for handling fine pitch & thin substrate high performance packages to support the increasing future demands of consumer electronics



Vision Assist Method for Common Change Kit